

SPECIFICATION

Product Part Number SD-102

Product Description: Secure Digital Memory Card Connector Normal Type

1. SCOPE

1.1 Content

This specification covers performance, tests and quality requirements for Secure Digital Card Connector These connectors are used to system signal transfer.

2. APPLICABLE DOCUMENTS

The following documents form a part of this specification to the extent specified herein. Unless otherwise specified, latest edition of the specification applies. In the event of conflict between requirements of this specification and product drawing, product drawing shall take precedence.

2.1. Commercial standards, specifications and report

- 2.1.1 MIL-STD -1344A
- 2.1.2 MIL-STD-202F

3. REQUIREMENTS

3.1 Design and Construction

Product shall be of design, construction and physical dimensions specified on applicable prouduct drawing.

3.2 Materials and finish

3.2.1 Contact : High performance copper alloy (Phosphor Bronze)

Finish : (a) Contact Area: Gold plated based on order information

(b)Solder Tail area: tin-lead 90/10 100u" MIN.(c) Underplate: 80u"min. Nickel-plated all over

3.2.2 Housing : LCP+30%GF, UL94V-0, Color: White.

3.2.3 Cover : Brass.

Finish : (a) Solder tail area: gold flash.

(b) Underplate: 80u"min. Nickel-plated all over

3.3. Ratings

3.3.1 Voltage: 200Volts DC, AC200 Volts(per pin)

3.3.2 Current: 0.5Amperes DC(per pin)

3.3.3 Operating Temperature : -20 to 90

3.4 Performance and Test Description

Product is designed to meet electrical, mechanical and environmental performance Requirements specified in Paragraph 3.5 All test are performed at ambient environmental condition perMIL-STD-1344 unless otherwise specified.

3.5. Test Requirements and Procedures Summary

Test Description Requirement		Procedure			
Examination of Product	Product shall meet requirements of Applicable product drawing and specification	Visual,dimensional and functional per Applicable quality inspection plan			

ELECTRICAL

Low-Signal Level	40m maximum initial	Mate subject connector with compatible				
Contact Resistance	R=20m maximum final	Connector as shown in.				
		MIL-STD-1344A,Method 3002.1				
	1000M minmum initial	Apply DC 500 10% Volts between				
Insulation Resistance	R=100m maximum final	Adjacent contacts of mated				
		Connectors for one minute.				
		MIL-STD-1344A, Method3001.1,				
		Test condition I				
Dielectric Withstanding at sea level for 1 minute.		Test between adjacent contacts of				
		Mated/unmated connectors.				
Voltage	No discharge, flashover or	MIL-STD-1344A, Method 3001.1,				
	Breakdown.	Test Condition I.				
	Current leakage:0.5A max					

MECHANICAL

Retention Force	100Gram(0.98N) minimum (per pin)	Mate connector with a suitable gauge For each opin at rate of 25 mm/min. Measure force when gauge reaches Surface of connector. MIL-STD-1344A,Method2012.1				
Insertion force	1000gGram(9.80N) maximum(for one product)	Mate connector with a suitable gauge For each pin at rate of 25 mm/min. Measure force when gauge reches Surfaces of connector. MIL-STD-1344A,Method2012.1				
Separation Force	150Gram (1.47N) minimum(For one Product)	Mate connector with a suitable gauge For each pin at rate of 25 mm/min. Measure force when gauge reches Surfaces of connector. MIL-STD-1344A,Method2012.1				
Durability	10000cycles. See Note(a)	The sample should be mounted in the Tester and fully mated and unmated The number of cycles apecified at the Rate of 25 mm/min. MIL-STD-1344A,Method2016				

Vibration, random	No electrical discontinuity greater Than 1 µ second. See Note (a).	The electrical load condition shall be 100 mA maximum for all contacts. The specimen shall then be subjected To the vibration specified by the Test-condition letter for the duration as Specified 1.5 hours in each of three Mutually perpendicular directions. MIL-STD-1344A,Method 2005.1, Condition V, Test Condition letter A.
Physical Shock	No electrical discontinuity greater Than 1 µ second. See Note (a).	Subject mated connectors to 50 Gs (peak value)half-sine shock pulses of 11 milliseconds duration. Three Shocks in each direction shall be Applied along the three mutually Perpendicular axes of the test Specimen (18 shocks). The electrical Load condition shall be 100mA Maximum for all contacts. MIL-STD-1344A,Method 2004,1. Condoition A
Solderability	Solderable area shall have Minimum of 95% solder coverage.	Subject the test area of contacts into Flux for 5~10seconds and then into Solder bath, controlled at 260 5 for 3 0.5seconds.

ENVIRONMENTAL

Temperature Cycling (thermal shock)	See Note(a)	Subject mated connectors to 25 cycles Between -55 and85 , 30 minutes Duration at both temperature Extremes. MIL-STD-1344A,Method 1003.1, ConditionA-1
Humidity-Temperature Cycling	See Note(a)	Subject mated connectors to 10 Humidity-temperature cycles between 25and65 ,at80-98%RH. MIL-STD-1344A,Method 1002.2, Type
Salt Spray	See Note(a)	Subject mated/unmated connectors to 5% salt-solution concentration,35 For 48 hours. MTL-STD-1344A,Method 1001.1, Condition B

		Subject mated connectors to				
Temperature life	See Note(a)	Temperature life at 85 for 250				
(Heat Aging)		hours.				
		MTL-STD-1344A,Method 1005.1,				
		Test temperature condition 3,				
		Test Time Condition B				
			1			

⁽a) Shall meet visual requirements, show no physical damage and shall meet requirements

3.6 Product Qualification and Test Sequence

	Test Group							
Test or Examination	1	2	3	4	5	6		
				Test	Sequence			
Examination of Product	1.7	1.6	1.3	1.10	1.5	1.9		
Low-Signal Level Contact Resistance	3.6	2.5		2.7	2.4	2.6		
Insulation Resistance				3.8		3.7		
Dielectric Withstanding Voltage				4.9		4.8		
Vibration		3						
Physical Shock		4						
Bounce Force	2.5							
Durability	4							
Solderability			2					
Temperature Cycling				5				
Humidity-Temperature Cycling				6				
Salt Spray					3			
Temperature Life(Heat Aging)						5		
Sample Size	8	8	4	8	8	8		

of Additional tests as specified in Test Sequence in Figure 1.